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Invigilator's Signature :	

CS/M.TECH(ECE-VLSI)/SEM-2/MVLSI-205D/2013 2013

ADVANCED MICRO & NANO DEVICES

Time Allotted : 3 Hours

Full Marks : 70

The figures in the margin indicate full marks. Candidates are required to give their answers in their own words as far as practicable.

Answer Q. No. **1** and any *four* from the rest. $5 \times 14 = 70$

- 1. Answer any *seven* of the following : $7 \times 2 = 14$
 - a) State the time-independent Schrödinger equation with proper notation.
 - b) Write down the proper potential distribution of a particle is trapped in 1D potential well.
 - c) Draw the Energy distribution, possible wave functions and probability distributions of electron in 1D infinite potential well.
 - d) Draw the band diagram of GaAs/AlGaAs HEMT with appropriate notations.

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- classify the CVD process according to the classification of operating pressure and physical characteristics of vapour used during CVD.
- f) Give the importance of high-k dielectrics with examples.
- g) What is EOT ?
- h) What are the differences between homo-junction and heterojunction ? Is the metal-semiconductor conduct heterojunction ?
- i) Write the effects of gate-oxide tunneling.
- 2. a) Solve the 1D Schrödinger equation for 1D infinite quantum well.
 - b) Write down the expression of wavefunction and energy of Nano Dot and Nano Wire and Nano Sheet. 8 + 6
- 3. a) Describe the Transmission Coefficient (T) and Reflection Coefficient (R) of Finite 1D Quantum Well with the Solution of respective Schrödinger equation in the class $E < V_0$ and $E > V_0$.
 - b) Describe the Tunneling Effect of the Quantum potential well. 10 + 4
- a) Describe the Physical structure, Energy Bank Diagram with potential distribution, I-V characteristics and Q-V characteristics of HEMT with suitable diagram.

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$$\label{eq:cs/M.TECH} \begin{split} & \text{CS/M.TECH(ECE-VLSI)/SEM-2/MVLSI-205D/2013} \\ \text{b)} & \text{Consider a n-type GaAs/Al_{0.3}Ga_{0.7}As HEMT at 300 K} \\ & \text{with the following parameters :} \\ & \text{Schottky barrier height } \Phi_{B0} = 0.9\,\text{V}, \text{ Space layer} \\ & \text{thickness } d_0 = 50\,\text{\AA}, \text{ barrier layer doping} \\ & N_D = 2 \times 10^{18}\,\text{cm}^{-3}, \text{ conduction band discontinuity} \\ & \Delta E_C = 0.24\,\text{eV}. \end{split}$$

Calculate the barrier thickness d at which the HEMT channel starts to turn on at a gate bias of $V_G = 0.5 \text{ V}$. Calculate the Sheet charge density at $V_G = 0.7 \text{ V}$. 8 + 6

- a) Describe Physical structure, Potential distribution I-V Characteristics and Tunneling Characteristics of an RTD.
 - b) Describe the Molecular Beam Epitaxy (MBE) with proper
 Schematic Diagram of useful apparatus. 6 + 8
- 6. a) State and explain MOS scaling laws.
 - b) Explain the effects of short channel in MOSFET. 6 + 8
- 7. a) How do the emitter and base be designed in a bipolar transistor for optimum gain ?
 - b) Explain the concept of 2-DEG. 10 + 4
- 8. a) Compare SiGe HBT and CMOS.
 - b) Compare HBT and HEMT.
 - c) Write down the operation of MESFET with diagram and mention its advantages. 3 + 3 + 8

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